

Resource Summary Report

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JEOL: JEM-ARM300F Transmission Electron Microscope

RRID:SCR_020174

Type: Tool

Proper Citation

JEOL: JEM-ARM300F Transmission Electron Microscope (RRID:SCR_020174)

Resource Information

URL: <https://www.jeolusa.com/PRODUCTS/Transmission-Electron-Microscopes-TEM/300-kV/JEM-ARM300F>

Proper Citation: JEOL: JEM-ARM300F Transmission Electron Microscope (RRID:SCR_020174)

Description: Transmission electron microscope that is designed to meet most advanced materials development requirements for atom by atom characterization and chemical mapping

Resource Type: instrument resource

Keywords: Jeol, JEOL, Transmission Electron Microscope, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: JEOL: JEM-ARM300F Transmission Electron Microscope

Resource ID: SCR_020174

Alternate IDs: Model_Number_JEM-ARM300F

Record Creation Time: 20220129T080349+0000

Record Last Update: 20260912T195931+0000

Ratings and Alerts

No rating or validation information has been found for JEOL: JEM-ARM300F Transmission Electron Microscope.

No alerts have been found for JEOL: JEM-ARM300F Transmission Electron Microscope.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.